Form PTO-1449 Modified

List of Patent and Publications
Cited by Applicant
(Use several sheets if necessary)

Docket No.	Serial No.
D5116-00002A	**09/673,427**
Applicant	
Saxena et al.	
Filing Date	**Group**
09/29/2000	**2812**

U. S. PATENT DOCUMENTS

Examiner Initial	Cite No.	Document No.	Date	Name	Class	Subclass
mrh	AA	4,795,964	1/3/89	Mahant-Shetti et al.	324	60
mrh	AB	4,939,681	7/3/90	Yokomizo et al.	364	578
mrh	AC	5,067,101	11/19/91	Kunikiyo et al.	364	578
mrh	AD	5,068,547	11/26/91	Gascoyne	307	443
mrh	AE	5,070,469	12/3/91	Kunikyo et al.	364	578
mrh	AF	5,286,656	2/15/94	Keown et al.	324	158
mrh	AG	5,301,118	4/5/94	Heck et al.	364	468
mrh	AH	5,438,527	8/1/95	Feldbaumer et al.	364	578
mrh	AI	5,486,786	1/23/96	Lee	327	378
mrh	AJ	5,502,643	3/26/96	Fujinaga	354	488
mrh	AK	5,625,268	4/29/97	Miyanari	318	696
mrh	AL	5,627,083	5/6/97	Tounai	438	18
mrh	AM	5,629,877	5/13/97	Tamegaya	364	578
mrh	AN	5,655,110	8/5/97	Krivokapic et al.	395	500
mrh	AO	5,703,381	12/30/97	Iwasa et al.	257	48
mrh	AP	5,778,202	7/7/98	Kuroishi et al.	395	306
mrh	AQ	5,790,479	8/4/98	Conn	368	118
mrh	AR	5,798,649	8/25/98	Smayling et al.	324	551
mrh	AS	5,867,033	2/2/99	Sporck et al.	324	763
mrh	AT	5,903,012	5/11/99	Boerstler	257	48
mrh	AU	5,966,527	10/12/99	Krivokapic et al.	395	500.35

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

Form PTO-1449 Modified List of Patent and Publications Cited by Applicant (Use several sheets if necessary) U.S. Department of Commerce Patent and Trademark Office	Docket No. **D5116-00002A**	Serial No. **09/675,427**
	Applicant **Saxena et al.**	
	Filing Date **09/29/2000**	Group **2812**

U. S. PATENT DOCUMENTS

Examiner Initial	Cite No.	Document No.	Date	Name	Class	Subclass
mel	AV	5,982,929	11/9/99	Ilan et al.	382	200
mel	AW	6,005,829	12/21/99	Conn	368	118
mel	AX	6,063,132	5/16/00	DeCamp et al.	716	5
mel	AY	6,066,179	5/23/00	Allan	716	4
mel	AZ	6,072,804	6/6/00	Beyers, Jr.	370	450
mel	BA	6,075,417	6/13/00	Cheek et al.	331	44
mel	BB	6,075,418	6/13/00	Kingsley et al.	331	57
mel	BC	6,118,137	9/12/00	Fulford, Jr. et al.	257	48
mel	BD	6,124,143	9/26/00	Sugasawara	438	18
mel	BE	6,134,191	10/17/00	Alfke	368	118

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Examiner Initial	Cite No.	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
MEH	BF	WALTON et al., "A Novel Approach for Reducing the Area Occupied by Contact Pads on Process Control Chips", *Proc IEEE 1990 Int. Conference on Microelectronic Test Structures*, Vol. 9, March 1990, pgs. 75-80
MEH	BG	BECKERS AND HILLTROP, "The Spidermask: A New Approach for Yield Monitoring Using Product Adaptable Tet Structures", *Proc IEEE 1990 Int. Conference on Microelectronic Test Structures*, Vol. 8, March 1990, pgs. 61-66
MEH	BH	LIEBMAN et al. "Understanding Across Chip Line Width Variation: The First Step Toward Optical Proximity Correction", SPIE Vol. 3051, pgs.124-136.
MEH	BI	PCT International Search Report, March 13, 2001
MEH	BJ	CONTI. M. et al., Parametric Yield Formulation of MOS IC's Affected by Mismatch Effect. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, May 1999, Vol. 18, No. 5, Pages 582-596
MEH	BK	TO. H. et al., Mismatch Modeling and Characterization of Bipolar Transistors for Statistical CAD. IEEE Transactions on Circuits and Systems–I: Fundamental Theory and Applications, July 1996, Vol. 43, No. 7, Pages 608-610
MEH	BL	FELT. E. et al., Measurement and Modeling of MOS Transistor Current Mismatch in Analog IC's, 1994 IEEE/ACM International Conference on Computer-Aided Design, November 1994, Pages 272-277
MEH	BM	MICHAEL. C. et al., A flexible Statistical Model for CAD of Submicrometer Analog CMOS Integrated Circuits, 1993, IEEE/ACM International Conference on Computer-Aided Design, November 1993, Pages 330-333
MEH	BN	OGRENCI. A. et al., Incorporating MOS Transistor Mismatches Into Training of Analog Neural Networks, Proceedings of NC, International ICSC/IFAC Symposium on Neural Computation, September 1998, Abstract only

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EXAMINER	DATE CONSIDERED April 15, 2004

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